

## 2018 IEEE INTERNATIONAL RELIABILITY PHYSICS SYMPOSIUM - Technical Program

### March 11th- 15th 2018, Hyatt Regency San Francisco Airport, Burlingame, CA

Tuesday • March 13				Wednesday • March 14				Thursday • March 15			
Time	D - Grand Ballroom			Time	D - GB	ABC	DEF	Time	D - GB	ABC	DEF
8:00 AM	GC Welcome & Introduction			8:00 AM	4A - GD	4B - WB	4C - SE	8:00 AM	6A -SR FOCUS	6B - FA	6C - PV
8:10 AM	Overview of Technical Program			8:05 AM	4A.1-191	4B.1-115	4C.1-163	8:05 AM	6A.1-FS1	6B.1-10	6C.1-I
8:30 AM	Awards			8:30 AM	4A.2-57	4B.2-43	4C.2-104	8:30 AM	6A.2-FS2	6B.2-I	6C.2-22
8:45 AM	Keynote Speaker1 - Nirmal Saxena, NVIDIA			8:55 AM	4A.3-165	4B.3-I	4C.3-92	8:55 AM	6A.3-FS3	6B.3-19	6C.3-40
9:30 AM	Keynote Speaker2 - Sanu Mathew, Intel			9:20 AM	4A.4-72	4B.4-117	4C.4-150	9:20 AM	6A.4-FS4	6B.4-I	6C.4-145
10:15 AM	Break (20min)			9:45 AM	4A.5-9	4B.5-45	4C.5-90	9:45 AM	6A.5-FS5	6B.5-30	Late
	D - GB	ABC	DEF	10:10 AM	Break (20min) - Author's Corner			10:10 AM	Break (20min) - Author's Corner		
10:35 AM	2A - TX	2B - WB	2C - EL	10:30 AM	4D - 3D FOCUS	4E - WB	4F-MR	10:30 AM	6D - MY	6E - RT	6F - PI
10:40 AM	2A.1-I	2B.1-I	2C.1-I	10:35 AM	4D.1-FS1	4E.1-I	4F.1-I	10:35 AM	6D.1-16	6E.1-116	6F.2-53
11:05 AM	2A.2-192	2B.2-I	2C.2-179	11:00 AM	4D.2-FS2	4E.2-85	4F.2-105	11:00 AM	6D.2-14	6E.2-138	6F.3-11
11:30 AM	2A.3-93	2B.3-I	2C.3-50	11:25 AM	4D.3-FS3	4E.3-160	4F.3-49	11:25 AM	6D.3-29	6E.3-189	6F.4-6
11:55 AM	2A.4-135	2B.4-I	2C.4-I	11:50 AM	4D.4-FS4	4E.4-174	4F.4-108	11:50 AM	Break (15min) - Author's Corner		
12:20 PM	Break (15min) - Author's Corner			12:15 PM	4D.5-FS5	4E.5-I	4F.5-I-ESREF	12:05 PM	Lunch (60min)		
12:35 PM	Lunch (60min)			12:40 PM	Break (15min) - Author's Corner			1:05 PM	6D - MY	6E - RT	6F - PI
1:35 PM	3A-GD	3B-WB FOCUS	3C - SR	12:55 PM	Lunch (80min)			1:10 PM	6D.4-48	6E.4-84	6F.5-114
1:40 PM	3A.1-26	3B.1-FS1	3C.1-111	2:15 PM	5A - TX	5B - 3D	5C - CR	1:35 PM	6D.5-164	6E.5-158	6F.6-183
2:05 PM	3A.2-98	3B.2-FS2	3C.2-I	2:20 PM	5A.1-119	5B.1-37	5C.1-I	2:00 PM	6D.6-190	6E.6-168	Late
2:30 PM	3A.3-74	3B.3-FS3	3C.3-81	2:45 PM	5A.2-I	5B.2-52	5C.2-180	2:25 PM	Late	Late	Late
2:55 PM	3A.4-77	3B.4-FS4	3C.4-I	3:10 PM	5A.3-137	5B.3-I	5C.3-181	2:50 PM	Break (15min) - Author's Corner		
3:20 PM	3A.5-97	3B.5-FS5	3C.5-I	3:35 PM	Break (20min) - Author's Corner			3:05 PM	Closing and 2019 Introduction - D - Grand Ball		
3:45 PM	Break (20min) - Author's Corner			3:55 PM	5A.4-133	5B.4-I	5C.4-I	Adjourn			
4:05 PM	3D - PR	3E - EL	3C - SR	4:20 PM	5A.5-39	5B.5-100	5C.5-75	3D	2.5D / 3D / Packaging	PR	Product Reliability
4:10 PM	3D.1-41	3E.1-153	3C.6-66	4:45 PM	5A.6-12	5B.6-148	5C.6-142	CR	Circuit Aging / Reliability	PV	Photovoltaics
4:35 PM	3D.2-15	3E.2-176	3C.7-182	5:10 PM	(20 min) Author's Corner			EL	Electrostatic Discharge/Latch UP	RT	Reliability Testing
5:00 PM	3D.3-154	3E.3-169	3C.8-I	Adjourn				FA	Failure Analysis	SE	Soft Errors
5:25 PM	(20 min) Author's Corner							GD	Dielectrics, Back-End	SR	System Reliability
Adjourn								MR	Metallization Reliability	TX	Transistors - Beyond CMOS
6:00 PM	Food & beverages (6:00)			6:00 PM	POSTER SESSION (6:00-9:0PM)			MY	Memory Reliability	WB	Wide Band Gap
9:00 PM	WORKSHOP (7:00-9:00PM)			9:00 PM				PI	Process Integration	FS	Focus Session